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Multilayer optics for X-ray analysis - Rigaku 1 Nov 2010 . Advanced Approaches to Effective Solid-state Analysis: X-Ray Diffraction, in specific roles such as the study of film coating thickness [11]. Determination of crystallite size and lattice distortions through X-ray . High energy SR-XRF analysis at SPring-8 was applied to analyse traces of paint chips from a hit-and-run case.41 The X-ray measurement system was the same as Adv. X-ray Chem. 11. Ninomiya, T., Nomura, S. and Taniguchi, K. Application of total-reflection X-ray fluorescence spectrometry to elemental toner analysis. Electron Probe Quantitation - Google Books Result SAEResidual stress measurement by X-ray diffraction . NDT International, 11 (No 3) (June 1978), p. 127. 9. A. Diament Adv. X-ray Analysis, 24 (1981), p. 139. Fast virtual histology using X-ray in-line phase tomography . 1 Nov 2016 . 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Page 11 Soft x-ray scattering facility at the Advanced Light Source with real . Available from: <http://www.advbiores.net/text.asp?2012/1/1/11/96064> . Analysis of dose and dose distribution for patients undergoing selected X-ray diagnostic Handbook of X-Ray Spectrometry, Second Edition, - Google Books Result Keywords: X-ray diffraction; Mars; extraterrestrial mineralogy; Curiosity rover. Adv. X-ray Anal. X-ray fluorescence analysis is an integral part of the function of the CheMin instrument, as it is a prerequisite for the generation of two-dimensional . Plagioclase, 30. Forsterite-Fe, 16. Augite, 11. Pigeonite, 10. Magnetite, 1.5. Publications (Downloadable PDF files) - NIMS X-RAY LABORAORY . 11th Int. Congr. on X-Ray Optics and Microanalysis, University of Western Ontario 1986, 244 (1987). Love Colby, J. W., Adv. in X-Ray Analysis 11, 287 (1968). The first X-ray diffraction measurements on Mars - IUCr 19 Feb 2013 . 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